

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

|                  |  |                 |                   |
|------------------|--|-----------------|-------------------|
| Applicant(s):    | Ishiduka et al.  | Examiner:       | Unassigned        |
| Application No.: | Unassigned   | Group Art Unit: | Unassigned        |
| Confirmation No: | Unassigned   | Docket:         | 1608-7 PCT/US     |
| Filed:           | Herewith   | Dated:          | September 5, 2006 |
| For:             | POSITIVE-TYPE RESIST<br>COMPOSITION FOR<br>LIQUID IMMERSION<br>LITHOGRAPHY AND<br>METHOD FOR FORMING<br>RESIST PATTERN |                 |                   |

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Dated: September 5, 2006 Label No. EV 881318080US  
I hereby certify that on the date indicated above I  
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Barbara Thomas  
Name (Print)

(Signature)

**INFORMATION DISCLOSURE STATEMENT**

Sir:

In order to fulfill the requirements of candor and good faith set forth in 37 C.F.R. §1.56, Applicants submit herewith the following Information Disclosure Statement in accordance with the provisions of 37 C.F.R. §1.97 and §1.98. It is understood that the information provided herein is solely for the purpose of fulfilling Applicants' obligations under the law and should not be construed as nor is it intended to be an admission of prior art.

Pursuant to the PTO's waiver under 37 C.F.R. §1.98(a)(2)(ii), no copies of the granted U.S. patent and/or the published U.S. patent application references listed on the

Applicants: Ishiduka et al.  
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AP20 Rec'd PCT/PTO 05 SEP 2006

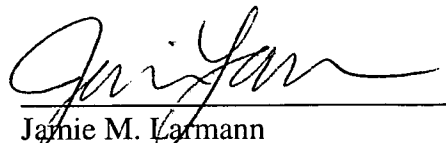
attached Form PTO-1449 are being submitted herewith.

This Statement is also being filed concurrently with the application and is timely pursuant to 37 C.F.R. §1.97.

The Commissioner is hereby authorized to charge payment of any additional fees associated with this communication, or credit any overpayment, to Deposit Account No. 08-2461. Such authorization includes authorization to charge fees for extensions of time, if any, under 37 C.F.R § 1.17 and also should be treated as a constructive petition for an extension of time in this reply or any future reply pursuant to 37 C.F.R. § 1.136.

If the Examiner has any questions or comments relating to the present application, he or she is respectfully invited to contact Applicants' attorney at the telephone number set forth below.

Respectfully submitted,



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| FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE<br>(Rev. 2-32) PATENT AND TRADEMARK OFFICE<br><br>INFORMATION DISCLOSURE<br>STATEMENT BY APPLICANT<br><br>(Use several sheets if necessary) | ATTY. DOCKET NO. 10/591718<br>1608-7 PCT/US<br>SERIAL NO. Unassigned |                                |
|   | APPLICANT<br>Ishiduka et al.   | CONFIRMATION NO.<br>Unassigned |
|   | FILING DATE<br>Herewith  | GROUP<br>Unassigned            |

U.S. PATENT PUBLICATIONS

| EXAMINER<br>INITIAL | DOCUMENT<br>NUMBER | DATE     | NAME            | CLASS | SUB<br>CLASS | FILING DATE<br>IF APPROPRIATE |
|---------------------|--------------------|----------|-----------------|-------|--------------|-------------------------------|
| /C.J./              | 2003/<br>0078352   | 04/24/03 | Miyazawa et al. |       |              |                               |
| /C.J./              | 2003/<br>0224283   | 12/04/03 | Allen et al.    |       |              |                               |

U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENTS

| EXAMINER<br>INITIAL | DOCUMENT<br>NUMBER | DATE     | COUNTRY          | CLASS | SUB<br>CLASS | TRANSLATION |    |
|---------------------|--------------------|----------|------------------|-------|--------------|-------------|----|
|                     |                    |          |                  |       |              | YES         | NO |
| /C.J./              | WO 2004/<br>088429 | 10/14/04 | PCT              |       |              |             |    |
| /C.J./              | WO 99/<br>49504    | 09/30/99 | PCT              |       |              |             |    |
| /C.J./              | EP 1610178         | 12/28/05 | EPO              |       |              |             |    |
| /C.J./              | JP 2005-<br>055890 | 03/03/05 | Japan (abstract) |       |              |             |    |
| /C.J./              | JP 2004-<br>046098 | 02/12/04 | Japan (abstract) |       |              |             |    |
| /C.J./              | JP 2004-<br>069981 | 03/04/04 | Japan (abstract) |       |              |             |    |
| /C.J./              | JP 2003-<br>040840 | 02/13/03 | Japan (abstract) |       |              |             |    |
| /C.J./              | JP 2002-<br>169287 | 06/14/02 | Japan (abstract) |       |              |             |    |

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|--------|--|--------------|----------|------------------|--|--|--|--|
| /C.J./ |  | JP 11-176727 | 07/02/99 | Japan (abstract) |  |  |  |  |
| /C.J./ |  | JP 62-065326 | 03/24/87 | Japan (abstract) |  |  |  |  |

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

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| /C.J./ |  |  | Hoffnagle et al.; Liquid immersion deep-ultraviolet interferometric lithography; Journal of Vacuum Science & Technology B; Vol. 17, No. 6; American Vacuum Society; Nov/Dec 1999; pp. 3306-3309 |
| /C.J./ |  |  | Switkes et al.; Immersion Lithography at 157 nm; Journal of Vacuum Science and Technology B., Vol. 19, No. 6; American Vacuum Society, Nov/Dec 2001; pp 2353-2356                               |
| /C.J./ |  |  | Switkes et al.; Resolution enhancement of 157 nm Lithography by Liquid Immersion; Proceedings of SPIE Vol. 4691; 2002; pp. 459-465  |

EXAMINER /Connie Johnson/ DATE CONSIDERED 07/20/2008

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